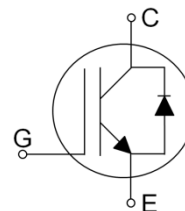


### Features:

- 1000V NPT Trench Technology
- High Speed Switching
- Low Conduction Loss
- Positive Temperature Coefficient
- Easy parallel Operation
- RoHS compliant
- JEDEC Qualification



### Applications :

Induction Heating, Soft switching application

Device	Package	Marking	Remark
TGL60N100ND1	TO-264	TGL60N100ND1	RoHS

### Absolute Maximum Ratings

Parameter	Symbol	Value	Unit	
Collector-Emitter Voltage	$V_{CES}$	1000	V	
Gate-Emitter Voltage	$V_{GES}$	$\pm 20$	V	
Continuous Current	$I_c$	$T_C = 25\text{ }^\circ\text{C}$	60	A
		$T_C = 100\text{ }^\circ\text{C}$	42	A
Pulsed Collector Current (Note 1)	$I_{CM}$	120	A	
Diode Continuous Forward Current	$I_F$	15	A	
Power Dissipation	$P_D$	$T_C = 25\text{ }^\circ\text{C}$	463	W
		$T_C = 100\text{ }^\circ\text{C}$	185	W
Operating Junction Temperature	$T_J$	-55 ~ 150	$^\circ\text{C}$	
Storage Temperature Range	$T_{STG}$	-55 ~ 150	$^\circ\text{C}$	
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	$T_L$	300	$^\circ\text{C}$	

Notes :

(1) Repetitive rating : Pulse width limited by max junction temperature

### Thermal Characteristics

Parameter	Symbol	Value	Unit
Maximum Thermal resistance, Junction-to-Case	$R_{\theta JC}$ (IGBT)	0.27	$^\circ\text{C}/\text{W}$
Maximum Thermal resistance, Junction-to-Case	$R_{\theta JC}$ (DIODE)	1.59	$^\circ\text{C}/\text{W}$
Maximum Thermal resistance, Junction-to-Ambient	$R_{\theta JA}$	25	$^\circ\text{C}/\text{W}$

**Electrical Characteristics of the IGBT**  $T_C=25^\circ\text{C}$ , unless otherwise noted

Parameter	Symbol	Test condition	Min	Typ	Max	Units
<b>OFF</b>						
Collector – Emitter Breakdown Voltage	$BV_{CES}$	$V_{GE} = 0V, I_C = 1mA$	1000	--	--	V
Zero Gate Voltage Collector Current	$I_{CES}$	$V_{CE} = 1000V, V_{GE} = 0V$	--	--	1	mA
Gate – Emitter Leakage Current	$I_{GES}$	$V_{CE} = 0V, V_{GE} = 20V$	--	--	$\pm 250$	nA

**ON**

Gate – Emitter Threshold Voltage	$V_{GE(TH)}$	$V_{GE} = V_{CE}, I_C = 60mA$	3.5	5.5	7.5	V
Collector – Emitter Saturation Voltage	$V_{CE(SAT)}$	$V_{GE} = 15V, I_C = 60A, T_J = 25^\circ\text{C}$	--	2.3	2.9	V
		$V_{GE} = 15V, I_C = 60A, T_J = 125^\circ\text{C}$	--	2.8	--	V

**DYNAMIC**

Input Capacitance	$C_{IES}$	$V_{CE} = 30V,$ $V_{GE} = 0V$ $f = 1MHz$	--	5600	--	pF
Output Capacitance	$C_{OES}$		--	150	--	pF
Reverse Transfer Capacitance	$C_{RES}$		--	115	--	pF

**SWITCHING**

Turn-On Delay Time	$t_{d(on)}$	$V_{CC} = 600V, I_C = 60A$ $R_G = 50\Omega, V_{GE} = 15V$ Inductive Load, $T_J = 25^\circ\text{C}$	--	230	--	ns
Rise Time	$t_r$		--	210	--	ns
Turn-Off Delay Time	$t_{d(off)}$		--	1480	--	ns
Fall Time	$t_f$		--	125	230	ns
Turn-On Switching Loss	$E_{ON}$		--	13.1	20	mJ
Turn-Off Switching Loss	$E_{OFF}$		--	6.3	10	mJ
Total Switching Loss	$E_{TS}$		--	19.4	30	mJ
Turn-On Delay Time	$t_{d(on)}$	$V_{CC} = 600V, I_C = 60A$ $R_G = 50\Omega, V_{GE} = 15V$ Inductive Load, $T_J = 125^\circ\text{C}$	--	200	--	ns
Rise Time	$t_r$		--	200	--	ns
Turn-Off Delay Time	$t_{d(off)}$		--	1670	--	ns
Fall Time	$t_f$		--	160	--	ns
Turn-On Switching Loss	$E_{ON}$		--	13.3	20	mJ
Turn-Off Switching Loss	$E_{OFF}$		--	7.6	11.4	mJ
Total Switching Loss	$E_{TS}$		--	20.9	31.4	mJ
Total Gate Charge	$Q_g$	$V_{CC} = 600V, I_C = 60A$ $V_{GE} = 15V$	--	270	405	nC
Gate-Emitter Charge	$Q_{ge}$		--	45	68	nC
Gate-Collector Charge	$Q_{gc}$		--	100	150	nC

**Electrical Characteristics of the DIODE**  $T_C=25^\circ\text{C}$ , unless otherwise noted

Parameter	Symbol	Test condition	Min	Typ	Max	Units	
Diode Forward Voltage	$V_{FM}$	$I_F = 15\text{ A}$	$T_J=25^\circ\text{C}$	--	1.7	2.2	V
			$T_J=125^\circ\text{C}$	--	1.8	--	
Diode Forward Voltage	$V_{FM}$	$I_F = 60\text{ A}$	$T_J=25^\circ\text{C}$	--	2.9	3.4	V
			$T_J=125^\circ\text{C}$	--	3.3	--	
Reverse Recovery Time	$t_{rr}$	$I_F = 60\text{ A},$ $di/dt=200\text{A/us}$	$T_J=25^\circ\text{C}$	--	310	465	ns
			$T_J=125^\circ\text{C}$	--	320	--	
Reverse Recovery Current	$I_{rr}$		$T_J=25^\circ\text{C}$	--	34	51	A
			$T_J=125^\circ\text{C}$	--	35	--	
Reverse Recovery Charge	$Q_{rr}$		$T_J=25^\circ\text{C}$	--	5270	7900	nC
			$T_J=125^\circ\text{C}$	--	5600	--	

# IGBT Characteristics

Fig. 1 Output characteristics

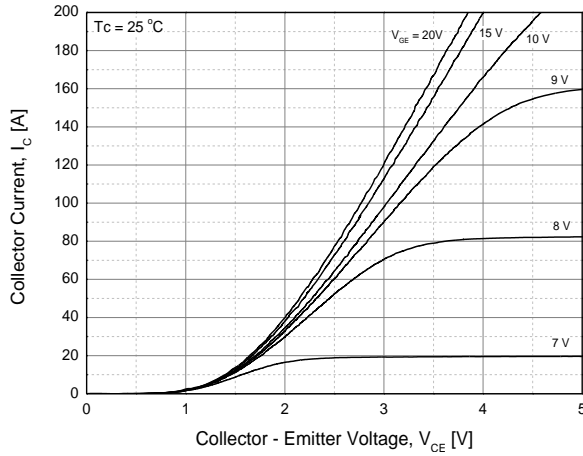


Fig. 2 Saturation voltage characteristics

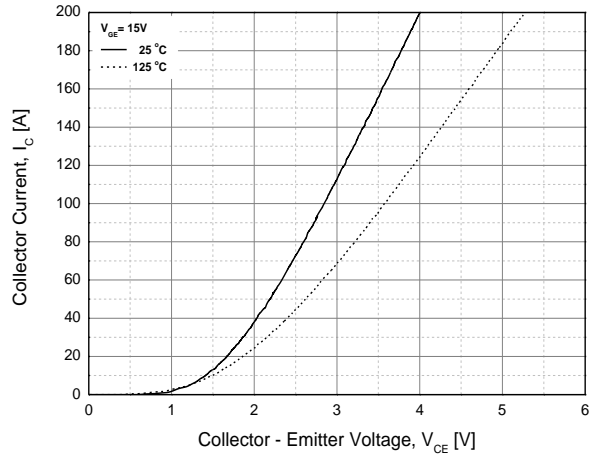


Fig. 3 Saturation voltage vs. collector current

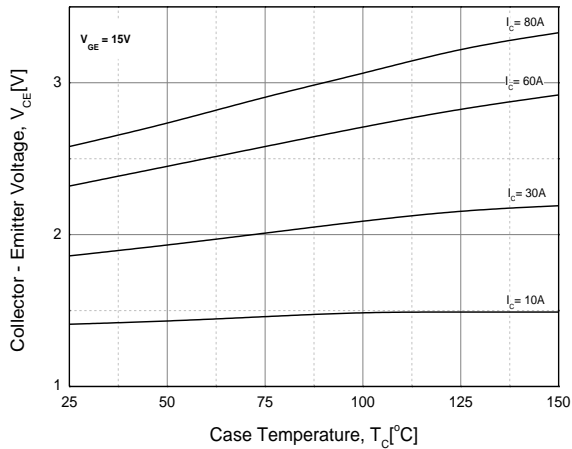


Fig. 4 Saturation voltage vs. gate bias

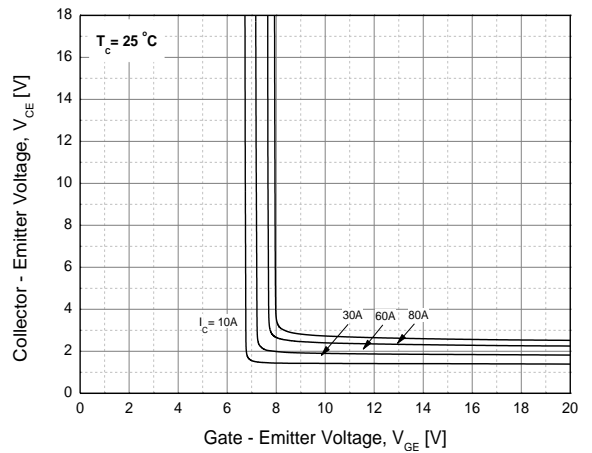


Fig. 5 Saturation voltage vs. gate bias

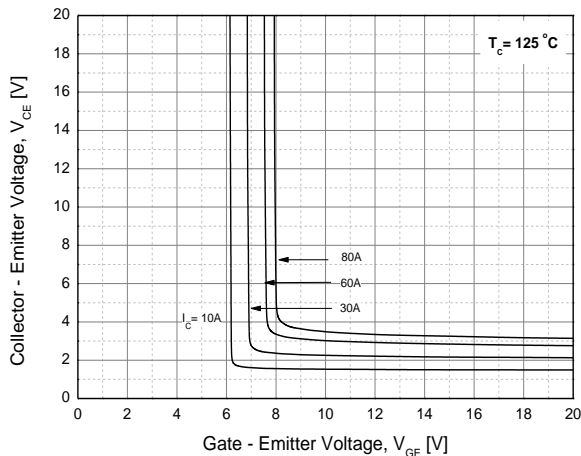
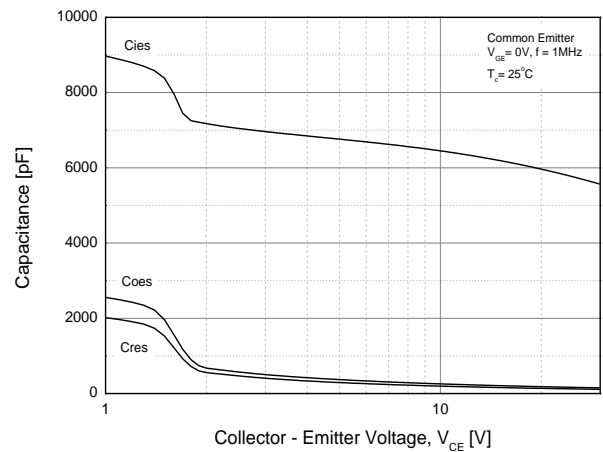


Fig. 6 Capacitance characteristics



# IGBT Characteristics

Fig. 7 Turn on time vs. gate resistance

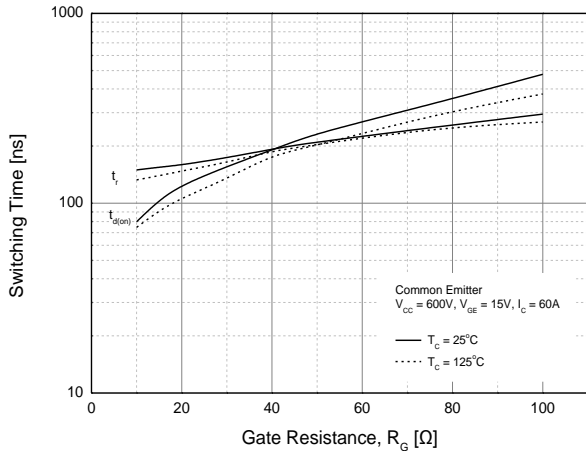


Fig. 8 Turn off time vs. gate resistance

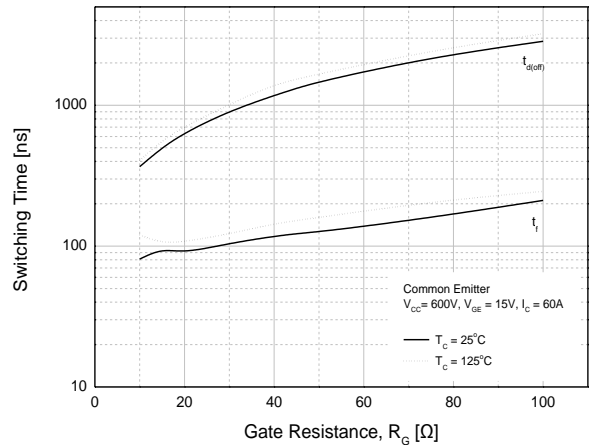


Fig. 9 Switching loss vs. gate resistance

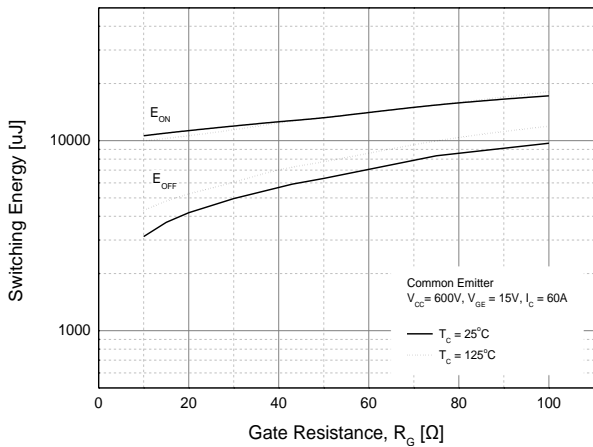


Fig. 10 Turn on time vs. collector current

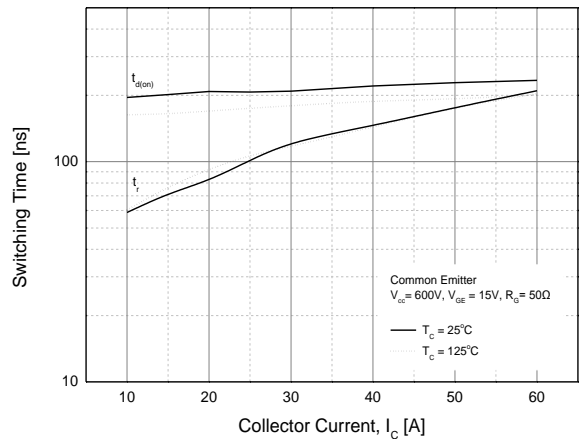


Fig. 11 Turn off time vs. collector current

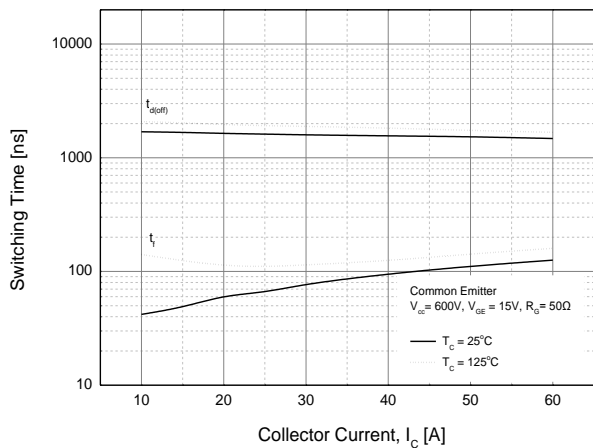
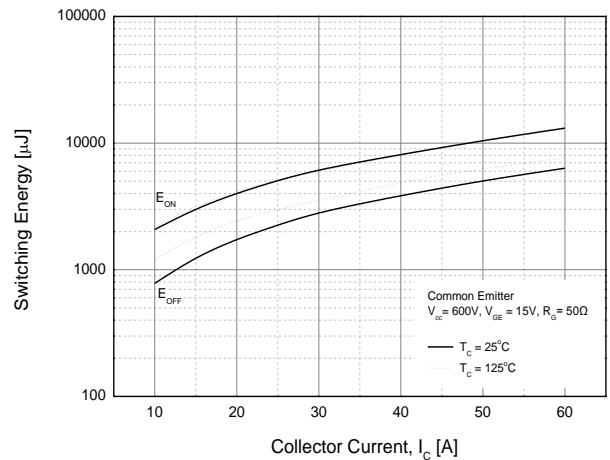


Fig. 12 Switching loss vs. collector current



# IGBT Characteristics

Fig. 13 Gate charge characteristics

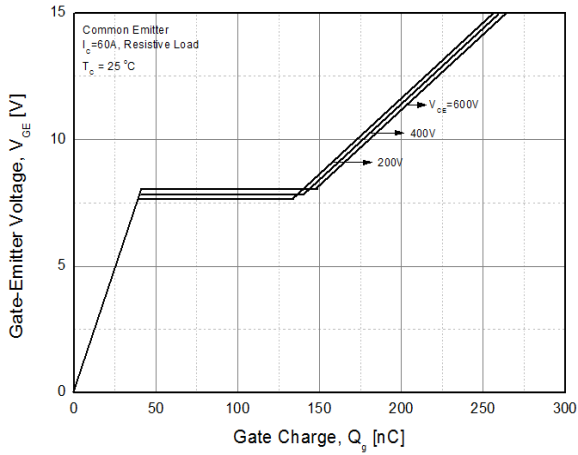


Fig. 14 SOA

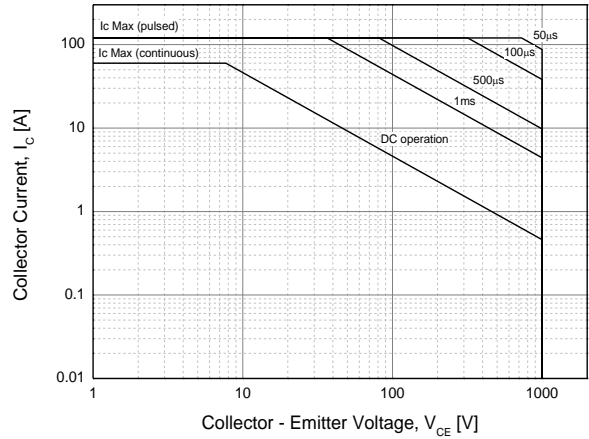


Fig. 15 RBSOA

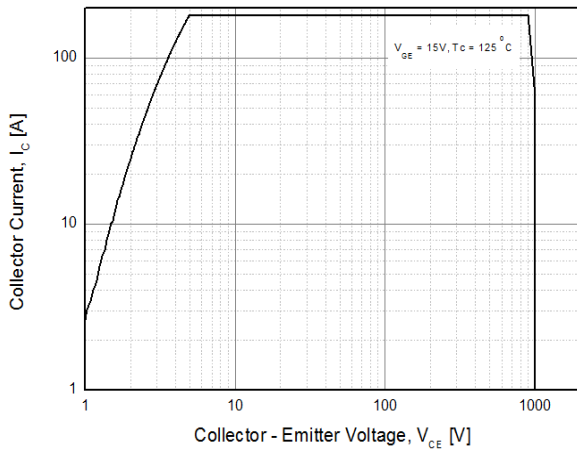


Fig. 16 Transient thermal impedance

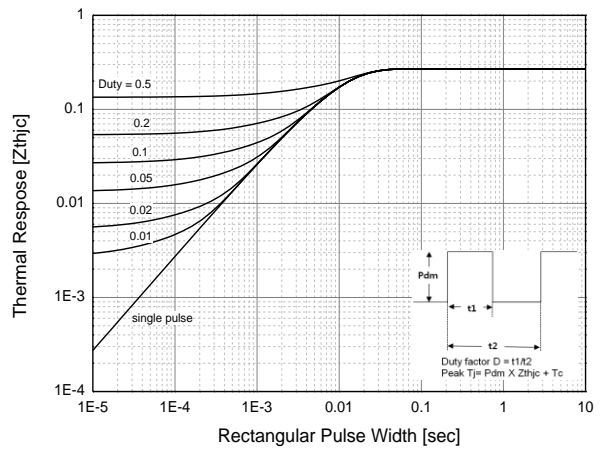
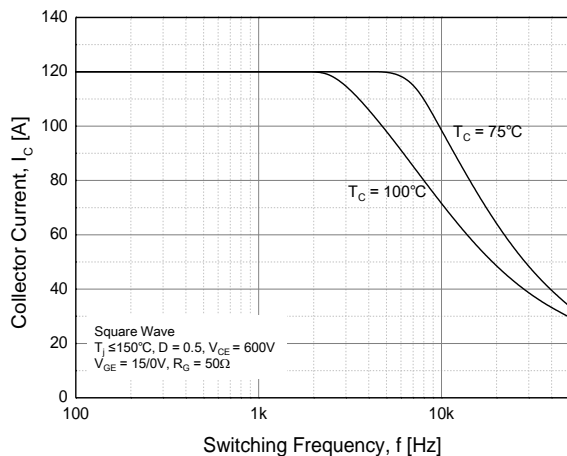


Fig. 17 Load Current vs. Frequency



## Diode Characteristics

Fig. 18 Conduction characteristics

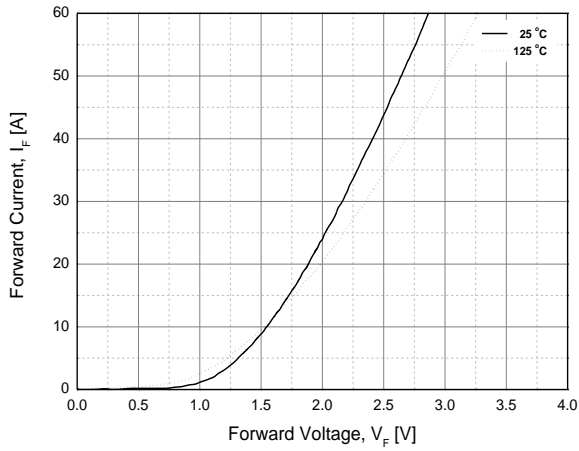


Fig. 19 Reverse recovery current vs. forward current

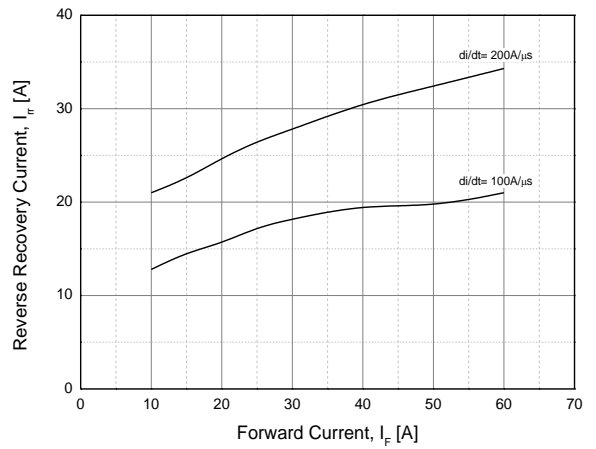


Fig. 20 Stored recovery charge vs. forward current

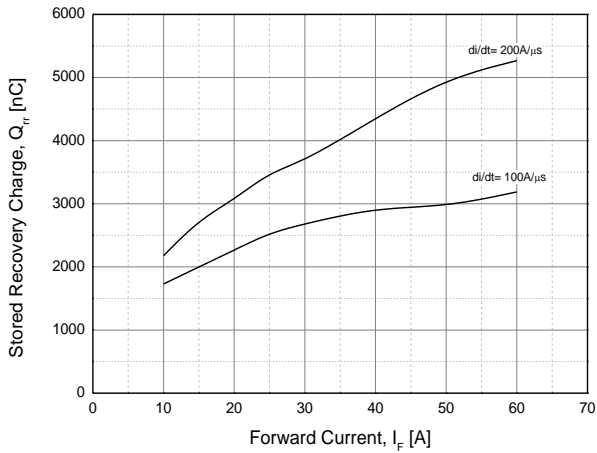
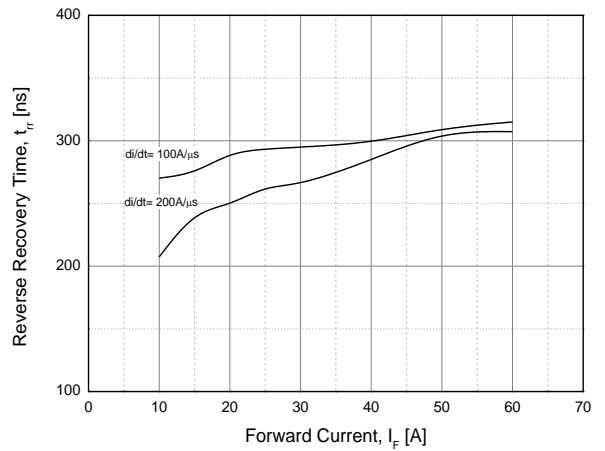
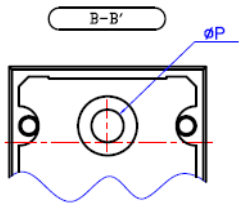
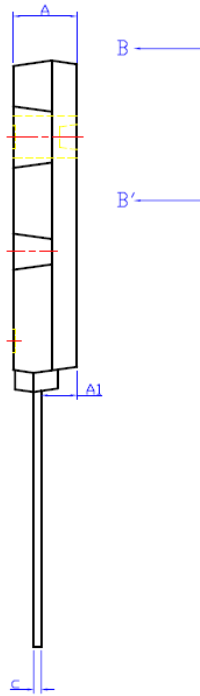
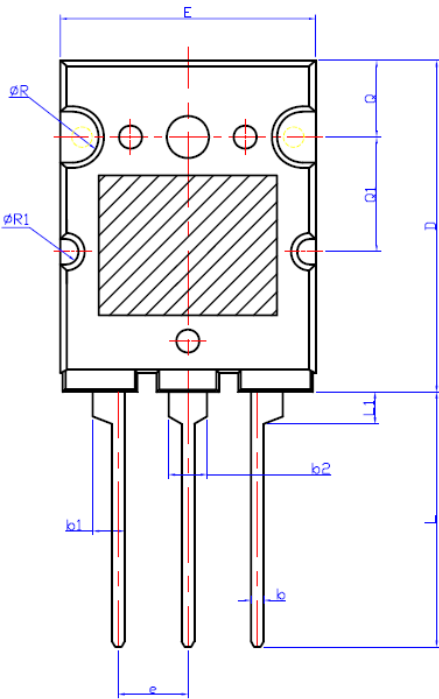


Fig. 21 Reverse recovery time vs. forward current



**Package Dimension : TO-264**



SYMBOL	MIN	NOM	MAX
A	4.80	5.00	5.20
A1	2.50	2.80	3.10
b	0.90	1.00	1.25
b1	2.30	2.50	2.70
b2	2.80	3.00	3.20
c	0.50	0.60	0.85
D	25.80	26.00	26.20
E	19.80	20.00	20.20
e	5.15	5.45	5.75
L	19.50	20.00	20.50
L1	2.40	2.50	2.60
ØP	3.00	3.20	3.40
Q	5.80	6.00	6.20
Q1	8.80	9.00	9.20
ØR	(2.00)		
ØR1	(1.00)		